## Notice of References Cited Application/Control No. 10/600,837 Examiner Krisna Lim Applicant(s)/Patent Under Reexamination THAKKAR ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0194049	12-2002	Boyd, John Edward	705/9
*	В	US-2003/0154116	08-2003	Lofton, Jeffrey C.	705/8
*	С	US-2002/0032592	03-2002	Krasnick et al.	705/8
*	D	US-7,082,402	07-2006	Conmy et al.	705/8
*	E	US-5,963,913	10-1999	Henneuse et al.	705/9
*	F	US-5,960,406	09-1999	Rasansky et al.	705/9
*	G	US-2003/0149606	08-2003	Cragun et al.	705/8
*	Н	US-2003/0171965	09-2003	Ratzlaff et al.	705/8
*	ı	US-2003/0191679	10-2003	Casati et al.	705/8
*	J	US-2003/0212586	11-2003	Majd et al.	705/8
*	К	US-2003/0220823	11-2003	Sartorius et al.	705/8
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					·
	Q					
	R					
	s	·				
	Т			,		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	<b>v</b>	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.